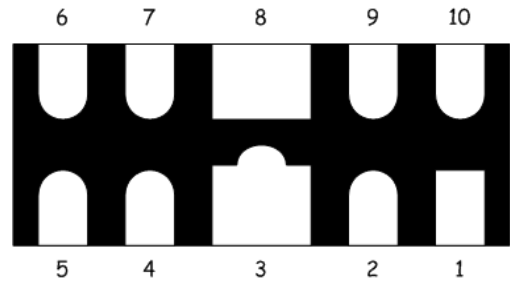


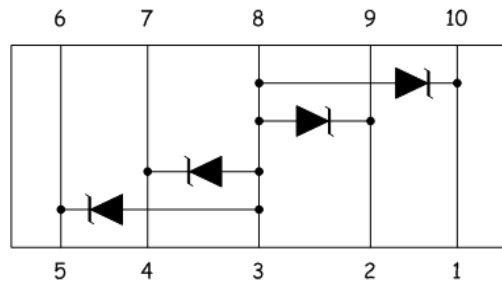
### Features

- Ultra low leakage: nA level
- Operating voltage: 3.3V
- Low clamping voltage
- Complies with following standards:
  - IEC 61000-4-2 (ESD) immunity test
    - Air discharge:  $\pm 25\text{kV}$
    - Contact discharge:  $\pm 15\text{kV}$
  - IEC61000-4-4 (EFT) 40A (5/50ns)
  - IEC61000-4-5 (Lightning) 10A (8/20 $\mu\text{s}$ )
- RoHS Compliant

### Dimensions DFN2510P10



### Pin Configuration

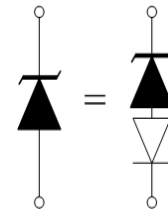


### Applications

- USB 3.0 /USB 3.1 Interfaces
- HDMI 1.4/HDMI2.0 Interfaces
- Video Graphics Cards
- Notebooks Desktops, and Servers
- Portable Instrumentation
- Industrial Controls

### Mechanical Characteristics

- Package: DFN2510P10
- Lead Finish: Lead Free
- UL Flammability Classification Rating 94V-0
- Quantity Per Reel:3,000pcs
- Reel Size:7 inch



Configuration per Line

### Absolute Maximum Ratings (Tamb=25°C unless otherwise specified)

Parameter	Symbol	Value	Unit
Peak Pulse Power (8/20 $\mu\text{s}$ )	Ppp	150	W
ESD per IEC 61000-4-2 (Air)	V <sub>ESD</sub>	$\pm 25$	Kv
ESD per IEC 61000-4-2 (Contact)		$\pm 15$	
Operating Temperature Range	T <sub>J</sub>	-55 to +125	°C
Storage Temperature Range	T <sub>STJ</sub>	-55 to +150	°C

## Electrical Characteristics (TA=25°C unless otherwise specified)

Part Number	Device Marking	V <sub>RWM</sub> (V)	V <sub>BR</sub> (V)	I <sub>T</sub> (mA)	V <sub>C</sub> @1A	V <sub>C</sub>		I <sub>R</sub> μA (Max)	C (pF) (Typ.) (Note 1)
						(Max)	(@A)		
ULC3314P10	U314	3.3	4.0	1	7	20	10	1	0.3

◆ Note 1 : Any I/O to GND

## Characteristic Curves

Fig1. 8/20μs Pulse Waveform

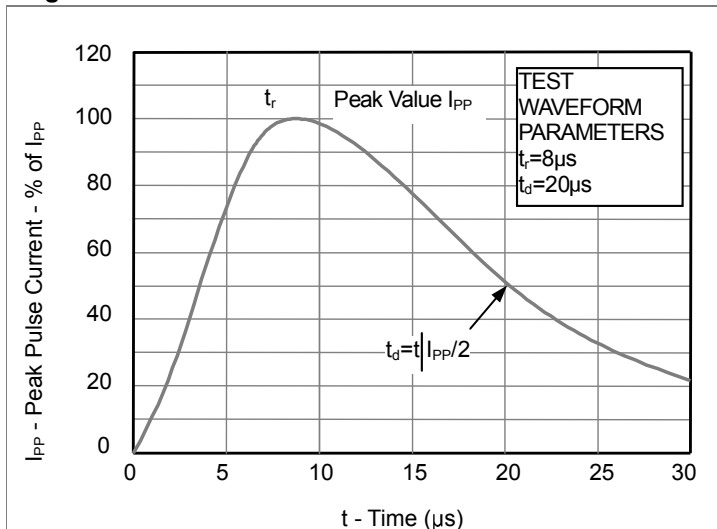


Fig2. ESD Pulse Waveform (according to IEC 61000-4-2)

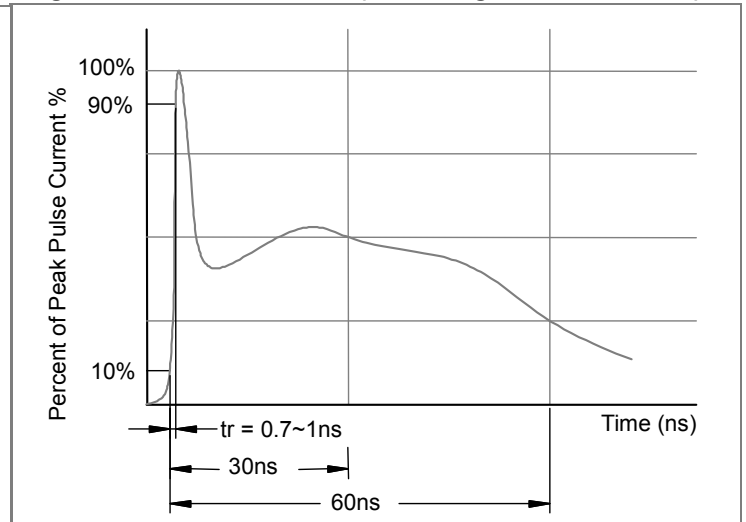
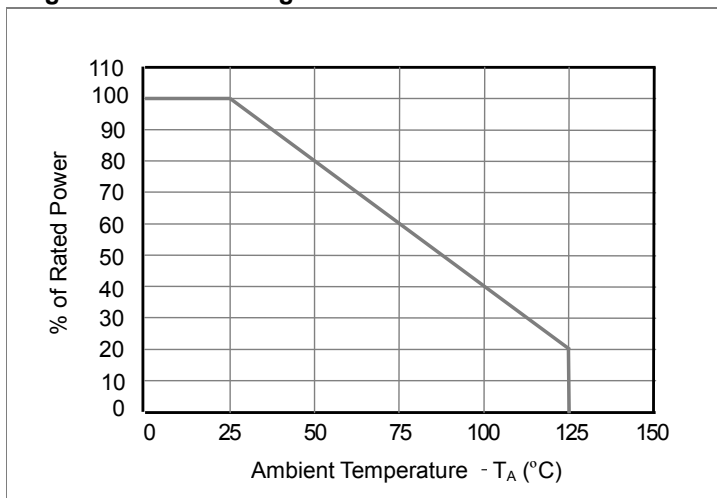
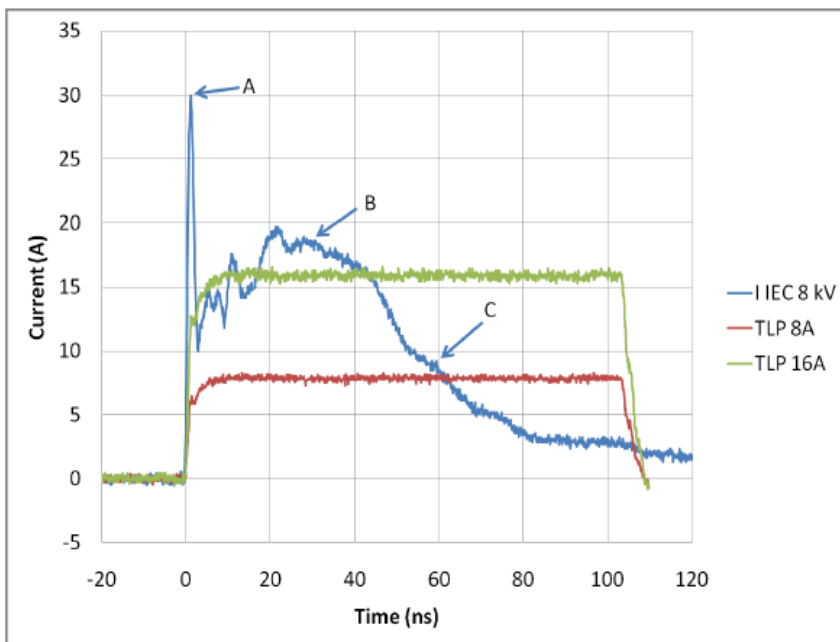


Fig3. Power Derating Curve



## Transmission Line Pulse (TLP)

Transmission Line Pulse (TLP) is a measurement technique used in the Electrostatic Discharge (ESD) arena to characterize performance attributes of devices under ESD stresses. TLP is able to obtain current versus voltage (I-V) curves in which each data point is obtained with a 100 ns long pulse, with currents up to 40 A. TLP was first used in the ESD field to study human body model (HBM) in integrated circuits, but it is an equally valid tool in the field of system level ESD. The applicability of TLP to system level ESD is illustrated in Figure 1, which compares an 8 kV IEC 61000-4-2 current waveform with TLP current pulses of 8 and 16 A. The current levels and time duration for the pulses are similar and the initial rise time for the TLP pulse is comparable to the rise time of the IEC 61000-4-2's initial current spike. This application note will give a basic introduction to TLP measurements and explain the datasheet parameters extracted from TLP for Yeashin Technology's protection products.



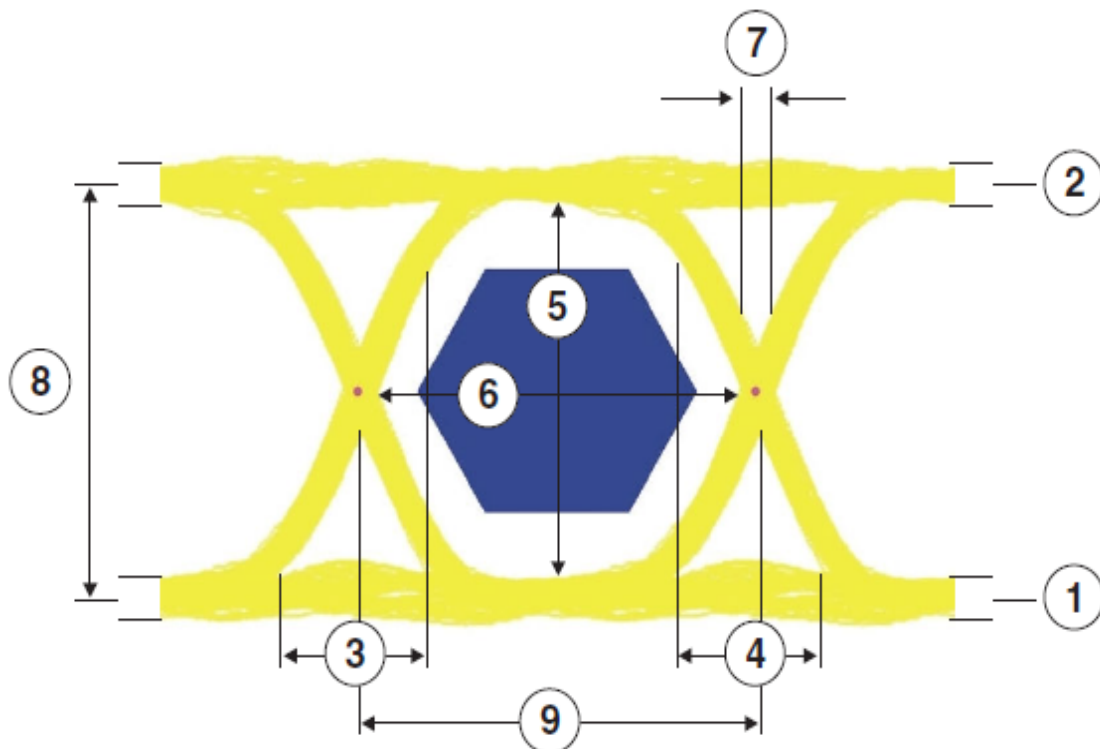
Comparison of a Current Waveform of IEC 61000-4-2 with TLP Pulses at 8 and 16 A.

The IEC 61000-4-2 ESD waveforms is true to the Standard and is shown here as captured on an oscilloscope. The points A, B, and C show the points on the waveforms specified in IEC 61000-4-2.

	4A (tp=100ns)	8A (tp=100ns)
ULC3314P10	6.5V(typ.)	14.5V(typ.)

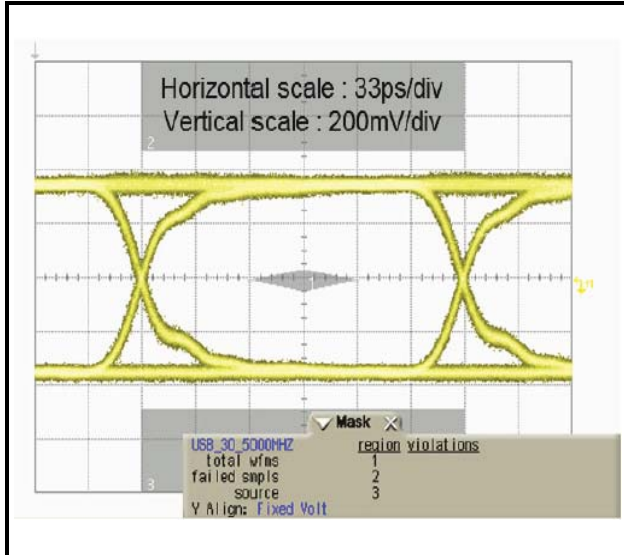
## Eye Diagram

- 1 Zero Level : measure of the mean value of the logical 0.
- 2 One Level : measure of the mean value of the logical 1.
- 3 Rise Time : measure of the transition time of the data from the 10% level to the 90% level on the upward slope.
- 4 Fall Time : measure of the transition time of the data from the 90% level to the 10% level on the downward slope.
- 5 Eye Height : measure of the vertical opening.  
Determine eye closure due to noise.
- 6 Eye Width : measure of the horizontal opening.  
Determine influence of jitter on the eye opening.
- 7 Deterministic Jitter : deviation of a transition from its ideal time caused by reflections relative to other transitions.
- 8 Eye Amplitude : difference between the logic 0 level and the logic 1 level histogram mean value.
- 9 Bit Rate : inverse of the bit period.

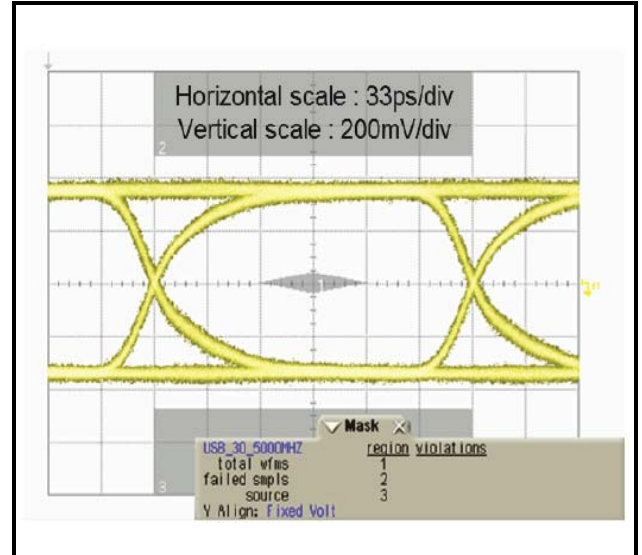


## Eye Diagram at 5Gbps and 10Gbps

### High Speed Test : 5Gbps

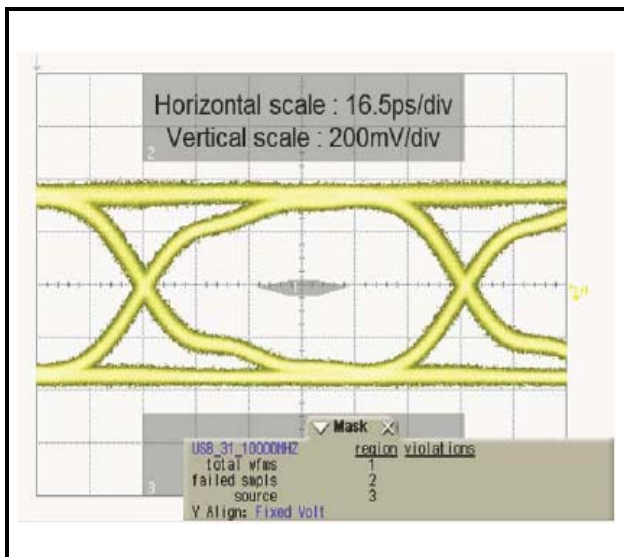


Eye Diagram -- USB 3.0 mask at 5.0Gbps.  
Without Component

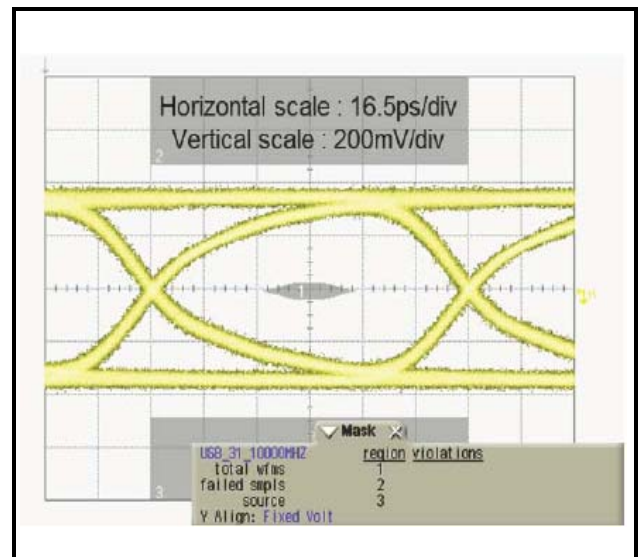


Eye Diagram -- USB 3.0 mask at 5.0Gbps.  
With Component

### High Speed Test : 10Gbps

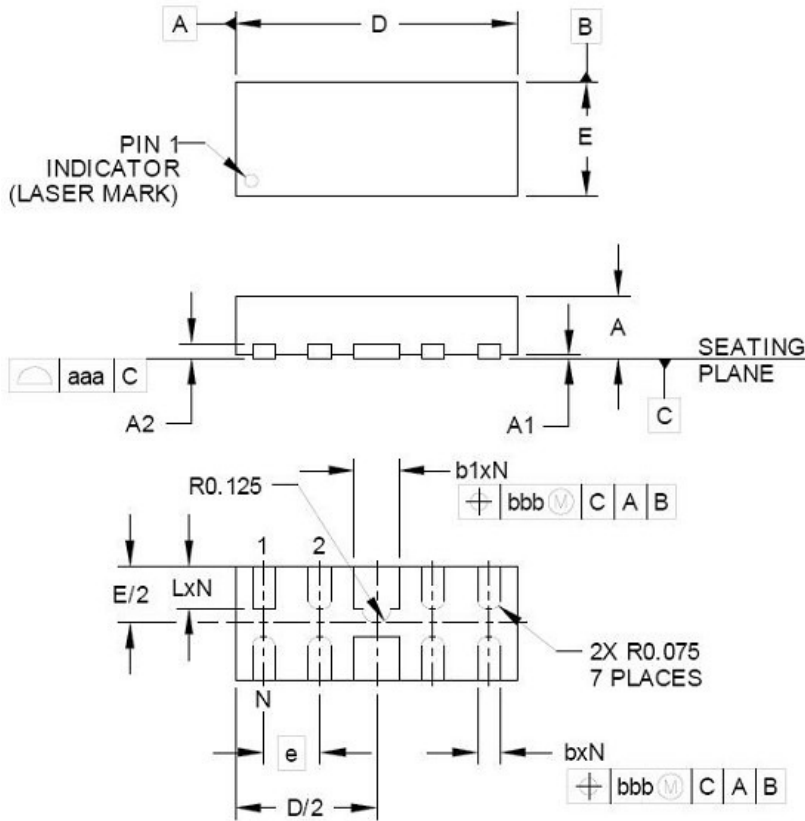


Eye Diagram -- USB 3.1 mask at 10.0Gbps.  
Without Component



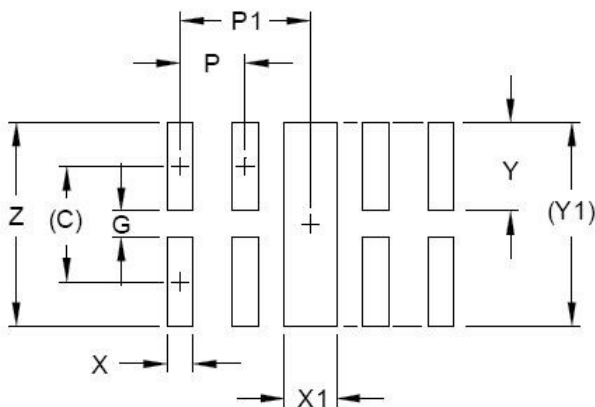
Eye Diagram -- USB 3.1 mask at 10.0Gbps.  
With Component

## DFN2510P10 PACKAGE OUTLINE & DIMENSIONS



DIM	INCHES			MILLIMETERS		
	MIN	NOM	MAX	MIN	NOM	MAX
A	.020	.023	.026	0.50	0.58	0.65
A1	0.00	.001	.002	0.00	0.03	0.05
A2	(.005)			(0.13)		
b	.006	.008	.010	0.15	0.20	0.25
b1	.014	.016	.018	0.35	0.40	0.45
D	.094	.098	.102	2.40	2.50	2.60
E	.035	.039	.043	0.90	1.00	1.10
e	.020 BSC			0.50 BSC		
L	.012	.015	.017	0.30	0.38	0.425
N	10			10		
aaa	.003			0.08		
bbb	.004			0.10		

### \* SOLDERING FOOTPRINT



DIM	DIMENSIONS	
	INCHES	MILLIMETERS
C	(.034)	(0.875)
G	.008	0.20
P	.020	0.50
P1	.039	1.00
X	.008	0.20
X1	.016	0.40
Y	.027	0.675
Y1	(.061)	(1.55)
Z	.061	1.55